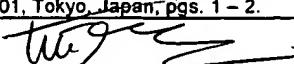


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 239339US2	SERIAL NO. New Application		
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yasuyoshi ITOH, et al.			
				FILING DATE Herewith	GROUP		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
TT	AA	5,768,192	06/16/98	Boaz EITAN			
AB							
AC							
AD							
AE							
AF							
AG							
AH							
AI							
AJ							
AK							
AL							
AM							
AN							
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
TT	AO	2000-260887	09/22/00	Japan	YES	NO	X ✓
TT	AP	5-75133	03/26/93	Japan (with English extract)	YES	NO	X ✓
TT	AQ	2002-26149	01/25/02	Japan (with partial English translation)	YES	NO	X ✓
AR							
AS							
AT							
AU							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
TT	AV	Ilan BLOOM, et al., "NRROM™ – A NEW NON-VOLATILE MEMORY TECHNOLOGY: FROM DEVICE TO PRODUCTS", Microelectronic Engineering 59, 2001, pgs. 213 – 223.					✓
TT	AW	Toshiyuki TOYOSHIMA, et al., "0.1µm LEVEL CONTACT HOLE PATTERN FORMATION WITH KF LITHOGRAPHY BY RESOLUTION ENHANCEMENT LITHOGRAPHY ASSISTED BY CHEMICAL SHRINK (RELACS)", IEEE, IEDM, 1998, pgs. 333 – 336.					✓
TT	AX	J. De BLAUWE, et al., "Si-Dot NON-VOLATILE MEMORY DEVICE", Extended Abstracts of the 2001 International Conference on Solid State Devices and Materials, Tokyo, 2001, pgs. 518 – 519.					✓
TT	AY	Boaz EITAN, et al., "CAN NRROM, A 2-BIT, TRAPPING STORAGE NVM CELL, GIVE A REAL CHALLENGE TO FLOATING GATE CELLS?", Presented at the International Conference on Solid State Devices and Materials, Tokyo, 1999, pgs. 1/3 – 3/3.					✓
TT	AZ	Eli LUSKY, et al., "ELECTRON DISCHARGE MODEL OF LOCALLY-TRAPPED CHARGE IN OXIDE-NITRIDE-OXIDE (ONO) GATES FOR NRROM™ NON-VOLATILE SEMICONDUCTOR MEMORY DEVICES", Presented at the Solid State Device and Materials Conference (SSDM 2001), Sep. 2001, Tokyo, Japan, pgs. 1 – 2.			<input type="checkbox"/> Additional References sheet(s) attached		✓
Examiner 				Date Considered 12/04			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							